- Single-Chip Interface Solution for the 9-Pin GeoPort™ Peripheral Data Circuit-Terminating Equipment (DCE) for the Intelligent Network Port
- Designed to Operate up to 4-Mbits/s Full Duplex
- Single 5-V Supply Operation
- 10-kV ESD Protection on Bus Terminals
- Backward Compatible with AppleTalk™ and LocalTalk™ LANs
- Combines Multiple Components into a Single Chip Solution
- Complements the SN75LBC776 9-Terminal GeoPort Host Data Terminal Equipment (DTE) Interface Device
- LinBiCMOS™ Process Technology

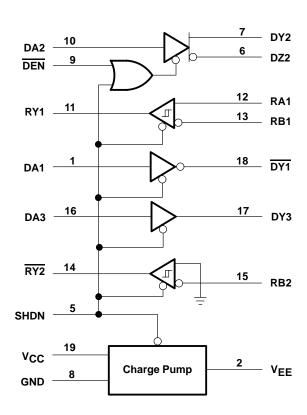
#### description

The SN75LBC777 is a low-power LinBiCMOS device that incorporate the drivers and receivers for a 9-pin GeoPort peripheral interface. GeoPort combines hybrid EIA/TIA-422-B and EIA/ TIA-423-B drivers and receivers to transmit data up to four-Mbit/s full duplex. GeoPort is a serial communications standard that is intended to replace the RS-232, AppleTalk, and printer ports all in one connector in addition to providing real-time data transfer capability. SN75LBC777 provides point-to-point connections between GeoPort-compatible devices with data transmission rates up to 4-Mbit/s full duplex over a 4-foot cable. Applications include connection to telephone, integrated services digital network (ISDN), digital sound and imaging, fax-data modems, and other traditional serial and parallel connections. The GeoPort is backwardly compatible to both LocalTalk and AppleTalk LANs.

While the SN75LBC777 is powered off ( $V_{CC} = 0$ ) the outputs are in a high-impedance state. When the shutdown (SHDN) terminal is high, the charge pump is powered down and the outputs are in a high-impedance state. When high, the driver enable ( $\overline{DEN}$ ) terminal puts the outputs of the differential driver into a high-impedance state.

#### **DW PACKAGE** (TOP VIEW) 20 DA1 □ ☐ GND 2 19 $V_{CC}$ $V_{\mathsf{EE}} \square$ C- $\Box$ 3 18 DY1 4 17 C+ 🗆 ☐ DY3 SHDN I 5 16 □ DA3 DZ2 6 15 RB2 7 14 DY2 □ $\square$ RY2 8 13 GND □ ☐ RB1 9 DEN $\square$ 12 □ RA1 DA2 [ 10 11

#### logic diagram (positive logic)





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### description (continued)

A switched-capacitor voltage converter generates the negative voltage required from a single 5-V supply using two  $0.33-\mu F$  capacitors. One capacitor is between the C+ and C- terminals and the other is between  $V_{EE}$  and ground.

The SN75LBC777 is characterized for operation over the 0°C to 70°C temperature range.

#### **DRIVER FUNCTION TABLE**

	INPUTS		ENA	ENABLE		OUTPUTS			
DA1	DA2	DA3	SHDN	DEN	DY1	DY2	DZ2	DY3	
Н	Х	Н	L	Х	L	Х	Х	Н	
L	X	L	L	Χ	Н	Х	Χ	L	
X	Н	X	L	L	Х	Н	L	Х	
X	L	X	L	L	Х	L	Н	Х	
OPEN	OPEN	OPEN	L	L	L	Н	L	Н	
X	X	X	Н	Χ	Z	Z	Z	Z	
X	X	X	Х	Н	Х	Z	Z	Х	
Х	Х	Χ	OPEN	OPEN	Z	Z	Z	Z	

H = high level, L= low level, X = irrelevant, ? = indeterminate, Z = high impedance (off)

#### **RECEIVER FUNCTION TABLE**

	INPUT	S	ENABLE	OUT	PUTS
RA1	RB1	RB2	SHDN	RY1	RY2
Н	L	Н	L	Н	L
L	Н	L	L	L	Н
OP	EN	OPEN	PEN L		Н
SHC	RT <sup>†</sup>	SHORT <sup>†</sup>	L	?	?
Х	X	Х	Н	Z	Z
Х	Χ	Х	OPEN	z	Z

 $t_{-0.2} \text{ V} < \text{V}_{\text{ID}} < 0.2 \text{ V}$ H = high level, L= low level, X = irrelevant, ? = indeterminate,



Z = high impedance (off)

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Positive supply voltage range, V <sub>CC.</sub> (see Note 1)	-0.5 to 7 V
Negative supply voltage range, V <sub>EE</sub> (see Note 1)	
Receiver input voltage range (RA1, RB1, RB2)	
Receiver differential input voltage range, V <sub>ID</sub>	
Receiver output voltage range (RY1, RY2)	
Driver output voltage range (Power Off)(DY1, DY2, DZ2, DY3)	
Driver output voltage range (Power On)(DY1, DY2, DZ2, DY3)	
Driver input voltage range (DA, SHDN, DEN)	
Electrostatic discharge (see Note 2)	
Bus Pins (Class 3 A)	10 kV
Bus Pins (Class 3 B)	600 V
All Pins (Class 3, A)	
All Pins (Class 3 B)	200 V
Continuous total power dissipation	See Dissipation Rating Table
Operating free-air temperature range, T <sub>A</sub>	0°C to 70°C
Storage temperature range, T <sub>Stq</sub>	65°C to 150 °C
Lead temperature 1,6 mm $(1/16)$ inch) from case for 10 seconds .	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltages values are with respect to the network ground terminal unless otherwise noted.

2. This rating is measured using MIL-STD-883C Method, 3015.7.

#### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{\scriptsize A}} \leq 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATE FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING
DW	1125 mW	9.0°C	720 mW



## recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>	4.75	5	5.25	V
High-level input voltage, VIH (DA, SHDN, DEN)	2		5.25	V
Low-level input voltage, V <sub>IL</sub> (DA, SHDN, DEN)			0.8	V
Receiver common-mode input voltage, V <sub>IC</sub>	-7		7	V
Receiver differential input voltage, V <sub>ID</sub>	-12		12	V
Voltage converter filter capacitance	0.33			μF
Voltage converter filter capacitor equivalent series resistance (ESR)	0		0.2	Ω
Operating free-air temperature, T <sub>A</sub>			70	°C

# driver electrical characteristics over operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CON	DITIONS	MIN	TYP	MAX	UNIT
V	High-level output voltage		R <sub>L</sub> = 12 kΩ		3.6	4.5		V
VOH	High-level output voltage	Single ended,	R <sub>L</sub> = 120 Ω		2	3.6		V
Voi	Low lovel output voltage	Single ended, See Figure 1 $R_L = 120 \ \Omega$ $R_L = 121 \ \Omega$ $R_L = 120 \ \Omega$ put voltage $R_L = 120 \ \Omega$ $R_L = 120 \ \Omega$ See Figure 2 $R_L = 120 \ \Omega$ See Figure 3 $R_L = 120 \ \Omega$ See Figure 3 $R_L = 120 \ \Omega$		-4.5	-3.6	V		
VOL	Low-level output voltage		R <sub>L</sub> = 120 Ω			-2.7	-1.8	V
IVODI	Magnitude of differential output	t voltage	$R_L = 120 \Omega$ ,	See Figure 2	4			V
Δ V <sub>OD</sub>	Change in differential voltage	magnitude					250	mV
Voc	Common-mode output voltage	•			-1		3	V
ΔV <sub>OC</sub> (SS)	Magnitude of change, common state output voltage	n-mode steady-	See Figure 3				200	mV
ΔVOC(PP)	Magnitude of change, common peak-to-peak output voltage	n-mode				700		mV
1	Cumply ourrant		SHDN = $\overline{DEN}$ = 0 V,	No Load		7	15	mΑ
Icc	Supply current		SHDN = $\overline{\text{DEN}}$ = 5 V,	No Load			100	μΑ
loz	High-impedance output curren	it	V <sub>CC</sub> = 0 or 5 V,	-10 ≤ V <sub>O</sub> ≤ 10 V			±100	μΑ
Ios	Short-circuit output current		V <sub>CC</sub> = 5.25 V, See Note 3	$-5 \text{ V} \leq \text{V}_{\text{O}} \leq 5 \text{ V},$		±170	±450	mA

NOTE 3: Not more than one output should be shorted at one time.



# driver switching characteristics over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
tPHL	Propagation delay time, high-to-low level output				40	75	ns
tPLH	Propagation delay time, low-to-high level output				40	75	ns
tPZL	Driver output enable time to low-level output	SHDN			25	100	μs
<sup>t</sup> PZH	Driver output enable time to high-level output	SHDN	Single-ended,		25	100	μs
t <sub>PLZ</sub>	Driver output disable time from low-level output	SHDN	$R_L = 120 \Omega$ , See Figure 4		30	100	ns
tPHZ	Driver output disable time from high-level output	SHDN	]		30	100	ns
t <sub>r</sub>	Rise time		Differential, RL = 120 Ω,	10	25	75	ns
t <sub>f</sub>	Fall time			10	25	75	ns
tPHL	Propagation delay time, high-to-low level output				40	75	ns
<sup>t</sup> PLH	Propagation delay time, low-to-high level output				40	75	ns
<b>.</b>	Driver output enable time to low-level output	SHDN			25	100	μs
<sup>t</sup> PZL		DEN			35	100	ns
	Driver autout anable time to high level autout	SHDN			25	100	μs
<sup>t</sup> PZH	Driver output enable time to high-level output	DEN			35	150	ns
4	Driver autout disable time from law law law at autout	SHDN	RL = 120 Ω, See Figure 5		30	100	ns
<sup>t</sup> PLZ	Driver output disable time from low-level output	DEN	]		30	100	ns
	Driver autout disable time from bigh lavel autout	SHDN			35	100	ns
<sup>t</sup> PHZ	Driver output disable time from high-level output	DEN	1		35	100	ns
t <sub>r</sub>	Rise time		7	10	25	75	ns
t <sub>f</sub>	Fall time		]	10	25	75	ns
tSK(P)	Pulse skew,  tpLH - tpHL					22	ns

### receiver electrical characteristics over free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CO	NDITIONS	MIN	TYP	MAX	UNIT
V <sub>IT+</sub>	Positive-going input threshold voltage					200	mV
V <sub>IT</sub> –	Negative-going input threshold voltage	]		-200			mV
V <sub>hys</sub>	Differential input voltage hysteresis (V <sub>IT+</sub> – V <sub>IT-</sub> )				50		mV
Vон	High-level output voltage (see Note 4)	$I_{OH} = 2 \text{ mA},$	VIC = 0	2	4.9		V
VOL	Low-level output voltage	$I_{OL} = -2 \text{ mA},$	VIC = 0		0.2	0.8	V
laa	Short circuit output ourrent	VO = 0		-85	-45		mA
los	Short-circuit output current	V <sub>O</sub> = 5.25 V			45	85	mA
R <sub>I</sub>	Input resistance	$V_{CC} = 0 \text{ or } 5.25 \text{ V},$	$-12 \text{ V} \le \text{V}_{I} \le 12 \text{ V}$	6	30	·	kΩ

NOTE 4: If the inputs are left unconnected, RA1 interprets this as a high-level input and RB1 and RB2 interpret this as a low-level input so that all outputs are at the high level.



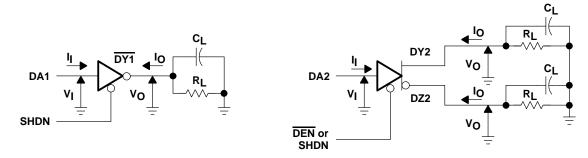
## SN75LBC777 SINGLE CHIP GEOPORT™/AppleTalk™ TRANSCEIVER

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## receiver switching characteristics over free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CO	NDITIONS	MIN	TYP	MAX	UNIT
tPHL	Propagation delay time, high-to-low level output				30	75	ns
tPLH	Propagation delay time, low-to-high level output				30	75	ns
t <sub>r</sub>	Rise time	$R_L = 2 k\Omega$ , See Figure 6	$C_L = 15 pF$ ,		15	30	ns
t <sub>f</sub>	Fall time	Occ riguic c			15	30	ns
tsk(p)	Pulse skew  tpLH-tpHL					20	ns
tPZL	Receiver output enable time to low-level output				35	100	ns
<sup>t</sup> PZH	Receiver output enable time to high-level output	Differential,	$C_L = 50 \text{ pF},$		35	100	ns
tPLZ	Receiver output disable time from low-level output	See Figure 7			21	100	ns
<sup>t</sup> PHZ	Receiver output disable time from high-level output				21	100	ns
tPZL	Receiver output enable time to low-level output				12	25	μs
<sup>t</sup> PZH	Receiver output enable time to high-level output	Single-ended,	C <sub>L</sub> = 50 pF,		12	25	μs
tPLZ	Receiver output disable time from low-level output	See Figure 7	_ ,		25	100	ns
tPHZ	Receiver output disable time from high-level output				125	400	ns





**TEST CIRCUIT** 

NOTES: A.  $C_L = 50 pF$ 

B. Driver 3 is a noninverting version of driver 1.

Figure 1. Single-Ended Driver DC Parameter Test Circuits

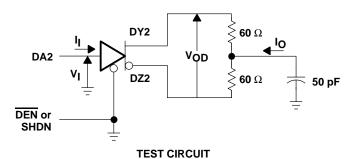
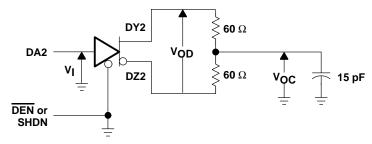
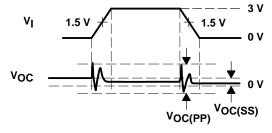


Figure 2. Differential Driver DC Parameter Test Circuit



**TEST CIRCUIT (see Note A)** 

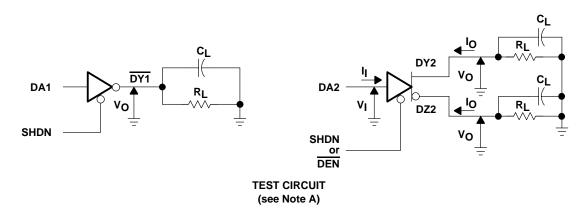


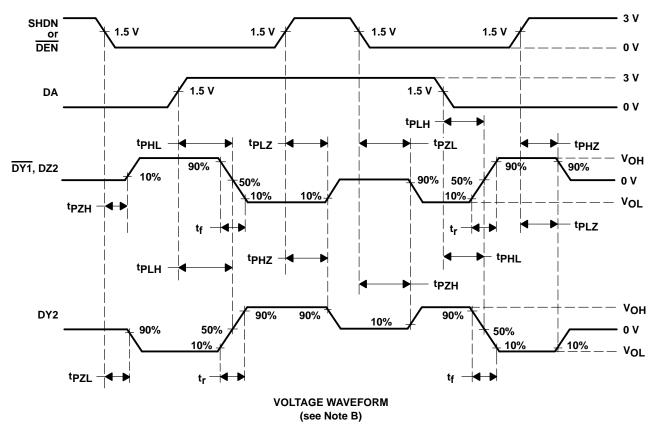
**VOLTAGE WAVEFORM** 

NOTE A. Measured 3dB Bandwidth = 300 MHz

Figure 3. Differential Driver Common-Mode Output Voltage Test Circuit and Waveform







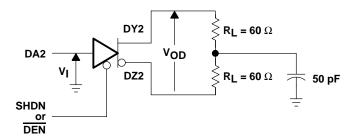
NOTES: A.  $C_L = 50 \text{ pF}, R_L = 120 \Omega$ 

B. The input waveform  $t_f$ ,  $t_f \le 10$  ns.

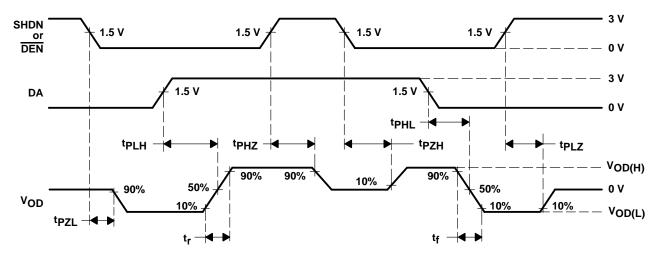
C. Driver 3 is a noninverting version of driver 1.

Figure 4. Single-Ended Driver Propagation and Transition Times Test Circuits and Waveform





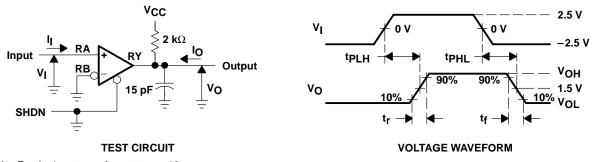
**TEST CIRCUIT** 



**VOLTAGE WAVEFORM** 

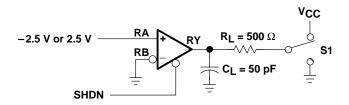
NOTE A: For the input waveform  $t_{\mbox{\scriptsize f}},\,t_{\mbox{\scriptsize f}}<$  = 10 ns

Figure 5. Differential Driver Propagation and Transition Times Test Circuit and Waveforms

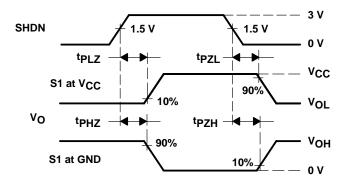


NOTE A: For the input waveform  $t_{\text{f}}$ ,  $t_{\text{f}}$  <= 10 ns

Figure 6. Receiver Propagation and Transition Times Test Circuit and Waveform



**TEST CIRCUIT** 

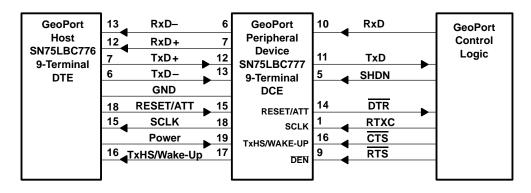


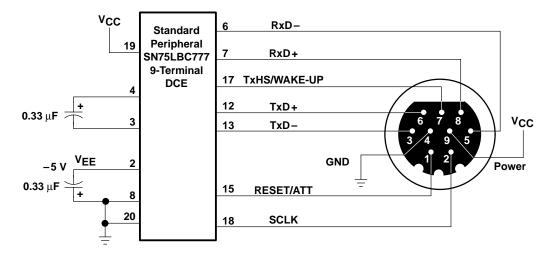
**VOLTAGE WAVEFORM** 

NOTE A: For the input waveform  $t_r$ ,  $t_f < = 10 \text{ ns}$ 

Figure 7. Receiver Enable and Disable Test Circuit and Waveforms

#### **APPLICATION INFORMATION**





NOTE A: A potential charge pump capacitor is the AVX 0805YC334MATXA or an equivalent.

Figure 8. GeoPort 9-terminal DCE Connection Application

## SN75LBC777 SINGLE CHIP GEOPORT™/AppleTalk™ TRANSCEIVER

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### generator characteristics

	PARAMETER	TEST (	CONDITIONS	232/	V.28	423/	<b>V</b> .10	56	2	UNIT
	PARAMETER	1531 0	TEST CONDITIONS		MAX	MIN	MAX	MIN	MAX	UNII
		Open circuit			25	4	6		13.2	V
IVOI	Output voltage magnitude	$3 \text{ k}\Omega \leq \text{R}_{\text{L}} \leq 3$	7 kΩ	5	15	N/	4	3.7		V
				N/	A	3.6		N/	A	V
los	Short-circuit output current	V <sub>O</sub> = 0			100		150		60	mA
R <sub>O</sub> (OFF)	Power-off source resistance	$V_{CC} = 0$ ,	V <sub>O</sub>   < 2 V	300		N/	4	300		Ω
I <sub>O(OFF)</sub>	Power-off output current	$V_{CC} = 0$ ,	V <sub>O</sub>   < 6 V	N/	A		±100	N/	4	μΑ
SR	Output voltage slew rate				30	N/	4	4	30	V/μs
		±3.3 V to ±3.	3 V	N/	A	N/	4	0.22	2.1	μs
t <sub>t</sub>	Output transition time	±3 V to ±3 V			0.04	N/	4	N/	A	ui†
		10% to 90%		N/	A		0.3	N/	4	ui†
VO(RING)	Output voltage ringing			N/	A		10%		5%	

 $<sup>^\</sup>dagger$  ui is the unit interval and is the inverse of the signaling rate (a.k.a. bit time).

#### receiver characteristics

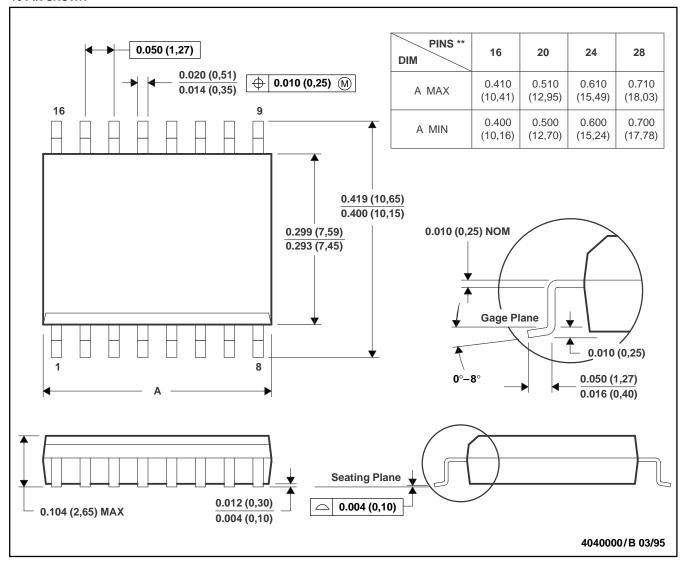
PARAMETER		TEST CONDITIONS	232/V.28		423/V.10		562		UNIT
		TEST CONDITIONS	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
$ V_I $	Input voltage			25		10		25	V
	Input voltage threshold	V <sub>I</sub>   < 15 V	-3	3	N/	4	-3	3	V
VIT	Input voltage threshold	V <sub>I</sub>   < 10 V	N/	4	-0.2	0.2	N/	4	V
Rį	Input registance	3 V <  V <sub>I</sub>   < 15 V	3	7	N/	Ą	3	7	kΩ
	Input resistance	V <sub>I</sub>   < 10 V	N/	A	4		N/	4	kΩ

### **MECHANICAL INFORMATION**

#### DW (R-PDSO-G\*\*)

#### PLASTIC SMALL-OUTLINE PACKAGE

#### **16 PIN SHOWN**



- NOTES: A. All linear dimensions are in inches (millimeters).
  - B. This drawing is subject to change without notice.
  - C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
  - D. Falls within JEDEC MS-013

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